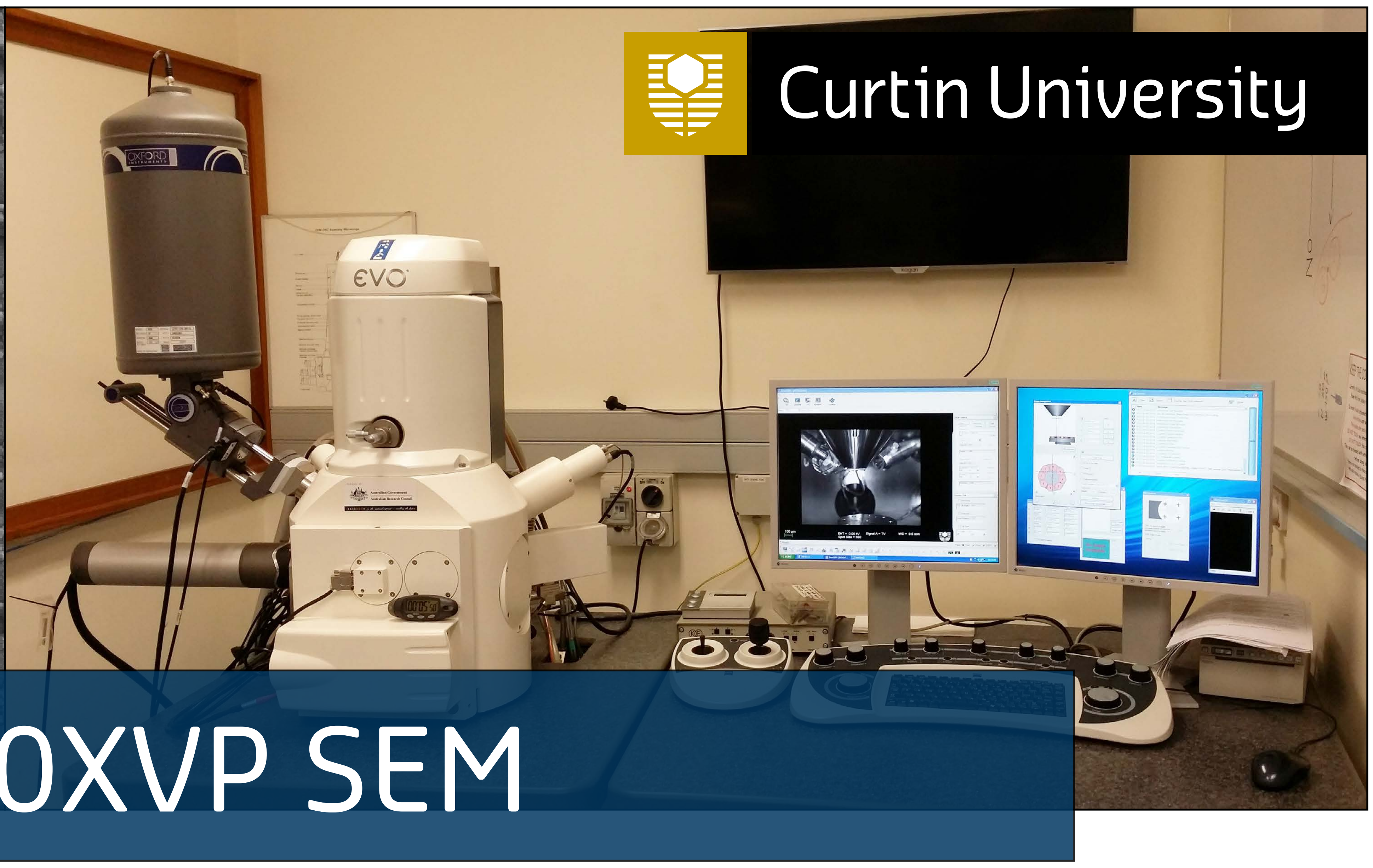
Curtin University



ZEISS EVO 40XVP SEM

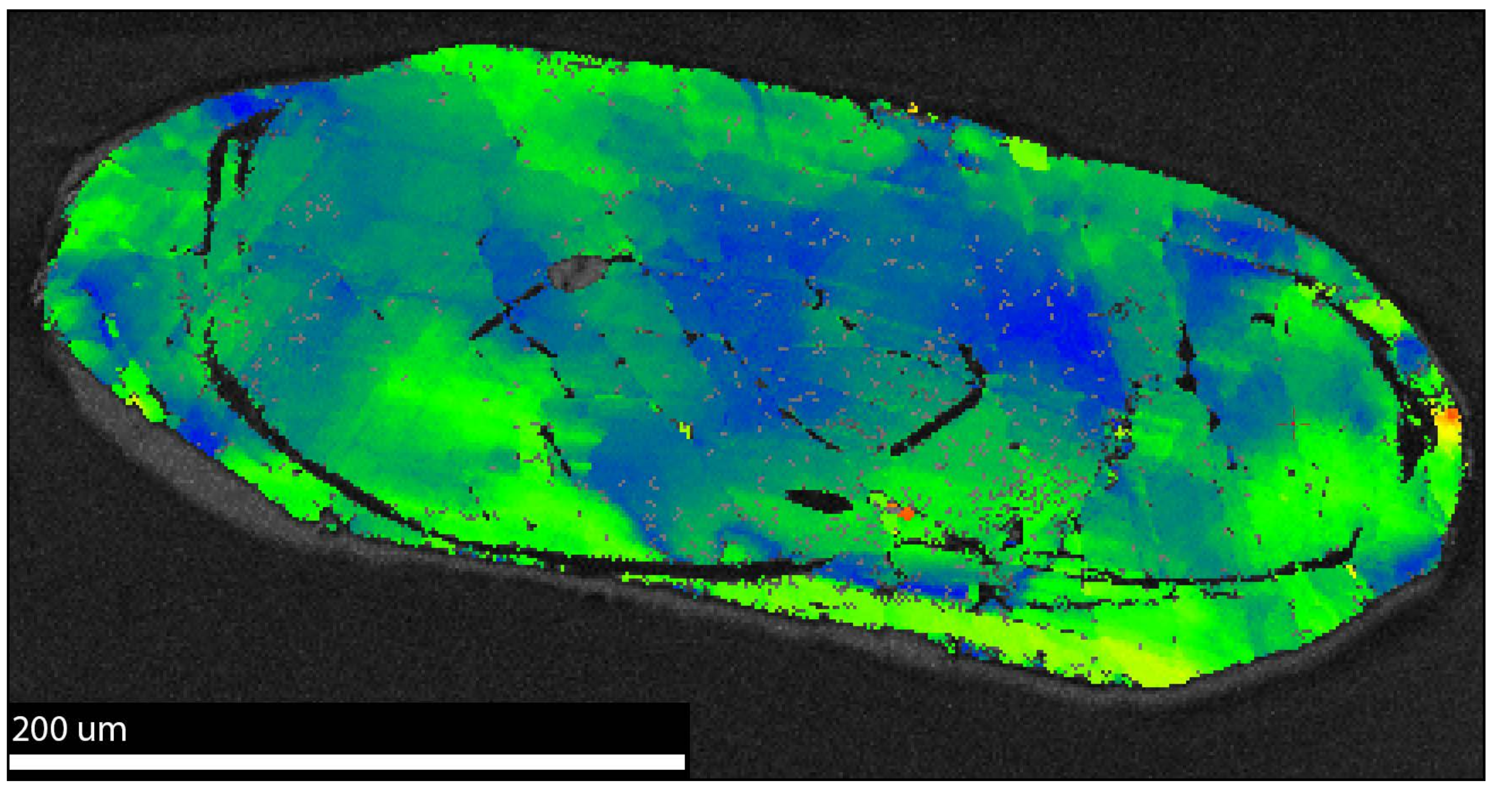
The EVO is a variable pressure scanning electron microscope (VP-SEM). The microscope is suitable for general purpose microstructural analysis at high vacuum, or for the analysis of non-conductive/ hydrated samples at lower vacuum.

Application Examples

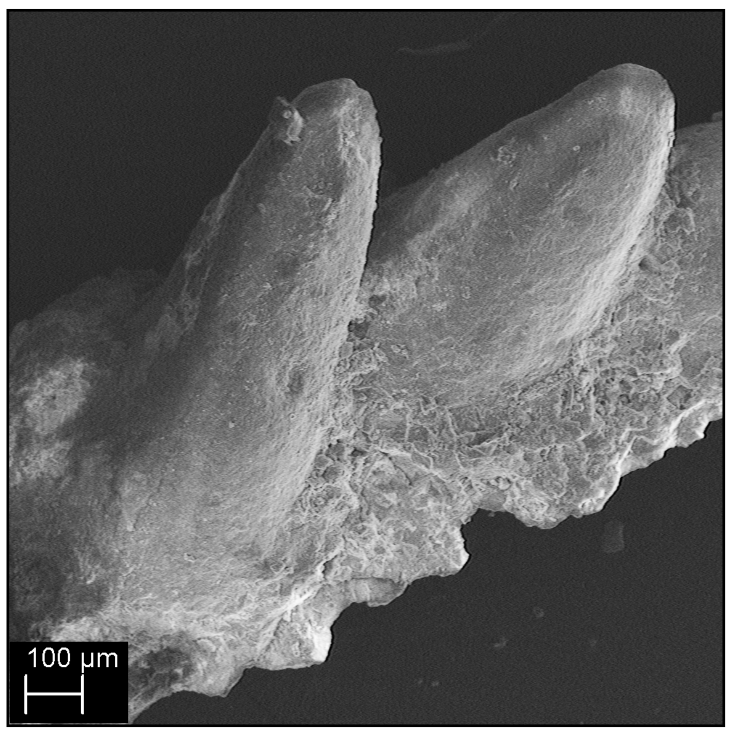
- Microstructural analysis of composite materials
- Investigation of corrosion products
- Identification and characterisation of asbestos fibres
- Measurement of discrete layers in carbon steels
- Imaging of prehistoric shark teeth
- Analysis of zircon growth structures prior to mass spectrometry analysis

Key Capabilities

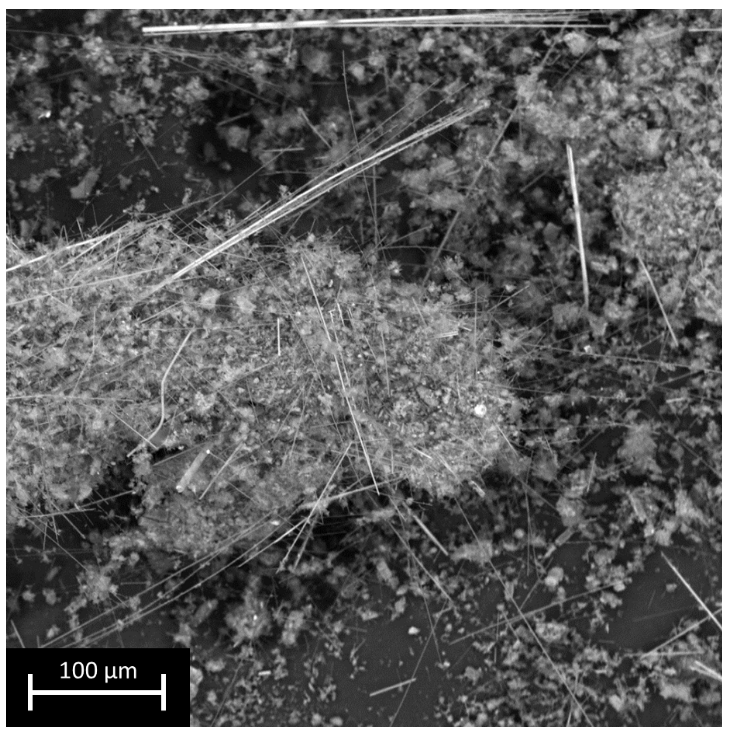
- Secondary Electron (SE) imaging
- Backscattered Electron (BSE) imaging
- Cathodoluminesence (CL) imaging
- Low vacuum secondary electron imaging
- Energy Dispersive X-ray Spectroscopy (EDS) point analysis and mapping
- Electron Backscatter Diffraction (EBSD) mapping



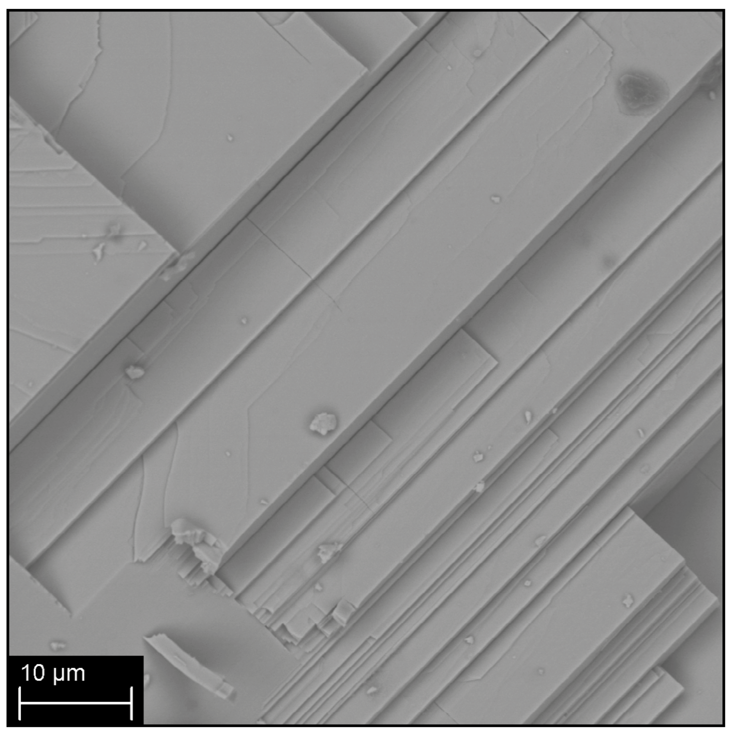
EBSD map of a zircon from South Africa



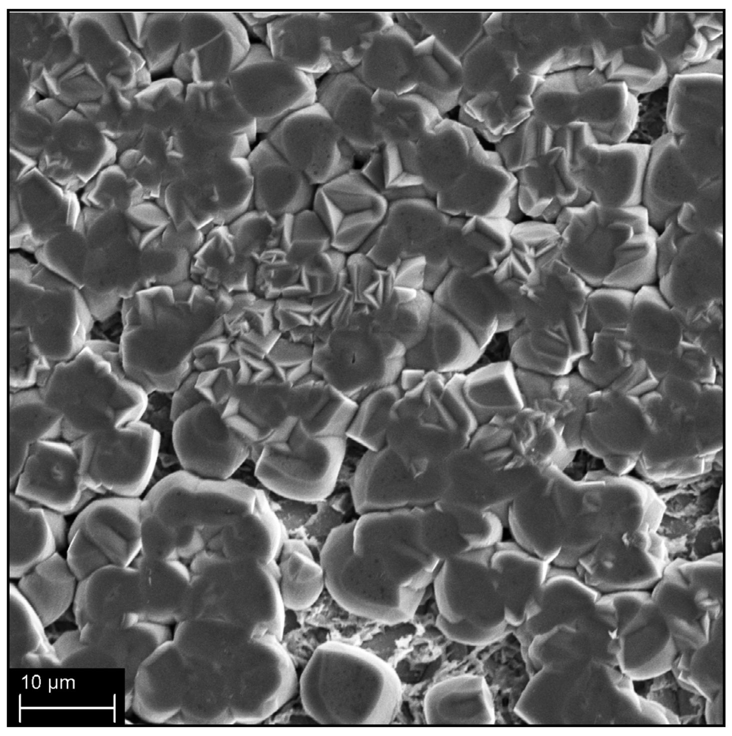
Stethacanthus tooth from the Carboniferous period



Mixed image of asbestos fibres



BSE image of galena



Corrosion products on carbon steel

For more information

Electron Microscope Facility

Phone: +61 8 9266 7511
Email: microscopy@curtin.edu.au

John de Laeter Centre
Isotope Research for the Earth and Environment